

(±)-*trans*-1,2,3,4,4a,9a-Hexahydroanthrone**Roger A. Lalancette*** and
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Correspondence e-mail:
rogerlal@andromeda.rutgers.edu**Key indicators**Single-crystal X-ray study
 $T = 296$ K
Mean $\sigma(\text{C}-\text{C}) = 0.004$ Å
 R factor = 0.064
 wR factor = 0.162
Data-to-parameter ratio = 14.2For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

The title compound, $\text{C}_{14}\text{H}_{16}\text{O}$, is largely flat and rigid, with near coplanarity between the ketone and the aromatic ring. The packing includes two intermolecular $\text{C}-\text{H}\cdots\text{O}=\text{C}$ close contacts.

Comment

The title compound, (I), is the end product in a synthetic sequence designed for a senior chemistry majors' undergraduate laboratory course (see *Experimental*), the final step of which involves acid-catalyzed internal acylation in *trans*-2-benzylcyclohexanecarboxylic acid (Scribner & Miller, 1965). Both the *trans* and the *cis* diastereomers of the product are known, and the equilibrium between them has been shown to favor (I) by a ratio of 88:12 at 298 K (Thompson & Long, 1988). Thus (I) is isolated more easily than the *cis* epimer, and because (I) is also the higher melting of the pair by some 9 K, it is more easily purified as well.

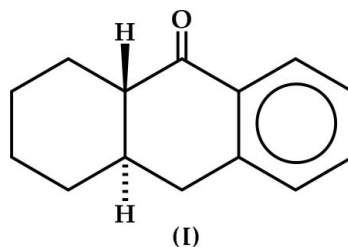


Fig. 1 shows the asymmetric unit for (I), with its numbering. The molecule has no significant flexibility and is largely flat except for the H atoms; the r.m.s. deviation for all non-H atoms from their average plane is 0.190 (3) Å; the partial flattening of the central ring in turn enforces a slight abnormal flattening in its fully saturated neighbor. Thus, the six internal tetrahedral bond angles for that ring are widened and vary from 110.9 (2) to 112.7 (3)°, while the ring-carbon torsion

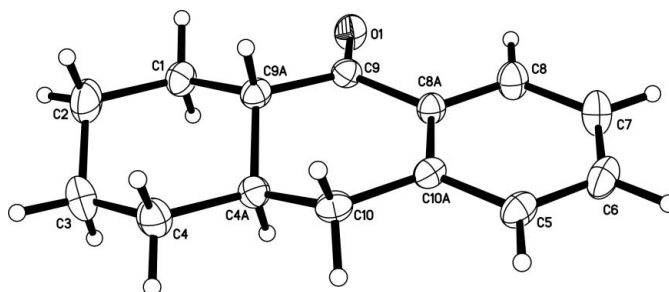


Figure 1
The molecular structure of (I), with its numbering. Displacement ellipsoids are drawn at the 20% probability level.

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angles all have absolute values between 51.6 (3) and 56.5 (4)°, rather than the 60° expected for cyclohexane. The dihedral angle for the ketone (C8A/C9/C9A/O1) *versus* the aromatic ring is 8.69 (11)°. This coplanarity provides almost the fullest possible degree of conjugation, reflected in the C=O stretching frequency of the IR spectrum (KBr, 1676 cm⁻¹).

Fig. 2 shows the packing arrangement, involving centrosymmetric pairing of molecules. Despite the short interplanar separations for the aromatic rings (3.87 Å within the chosen cell, 3.67 Å across the *bc* face), π - π stacking is absent because of the offset of the aromatic rings from one another, evident in Fig. 2. Within the 2.7 Å range we routinely survey for non-bonded dipolar packing interactions (Steiner, 1997), two intermolecular C—H...O=C close contacts were found, involving H9A (2.66 Å) in a centrosymmetrically related molecule, and H5A (2.61 Å) in a molecule translationally related along *b* (Table 1).

Experimental

Friedel–Crafts acylation of benzene with *cis*-cyclohexane-1,2-dicarboxylic acid anhydride (AlCl₃) yielded 2-benzoylcyclohexanecarboxylic acid, which was subjected to intentional base-catalyzed stereochemical equilibration to provide the *trans* epimer (Scribner & Miller, 1965; Lalancette *et al.*, 1996). Subsequent catalytic hydrogenolysis, employing Pd/C in acetic acid, gave *trans*-2-benzoylcyclohexanecarboxylic acid, and this was then cyclized at room temperature with H₂SO₄ (Scribner & Miller, 1965). Sublimation of (I) and recrystallization from hexane provided material of X-ray quality (m.p. 382 K).

Crystal data

C₁₄H₁₆O
M_r = 200.27
 Triclinic, *P* $\bar{1}$
a = 7.533 (5) Å
b = 8.067 (7) Å
c = 9.317 (5) Å
 α = 82.06 (6)°
 β = 80.95 (3)°
 γ = 81.31 (7)°
V = 548.9 (7) Å³
Z = 2
D_x = 1.212 Mg m⁻³
 Mo *K* α radiation
 Cell parameters from 25 reflections
 θ = 3.4–9.7°
 μ = 0.07 mm⁻¹
T = 296 (2) K
 Pallelepiped, colourless
 0.50 × 0.25 × 0.07 mm

Data collection

Siemens P4 diffractometer
 $\omega/2\theta$ scans
 Absorption correction: numerical (SHELXTL; Sheldrick, 1997)
T_{min} = 0.981, *T_{max}* = 0.989
 2406 measured reflections
 1926 independent reflections
 1101 reflections with *I* > 2 σ (*I*)
R_{int} = 0.035
 θ_{\max} = 25.0°
h = -8 → 1
k = -9 → 9
l = -11 → 11
 3 standard reflections every 97 reflections
 intensity decay: variation <2.5%

Refinement

Refinement on *F*²
R[*F*² > 2 σ (*F*²)] = 0.064
wR(*F*²) = 0.162
S = 1.03
 1926 reflections
 136 parameters
 H-atom parameters constrained
 $w = 1/[\sigma^2(F_o^2) + (0.0559P)^2 + 0.1357P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\max} < 0.001$
 $\Delta\rho_{\max} = 0.13 \text{ e \AA}^{-3}$
 $\Delta\rho_{\min} = -0.14 \text{ e \AA}^{-3}$

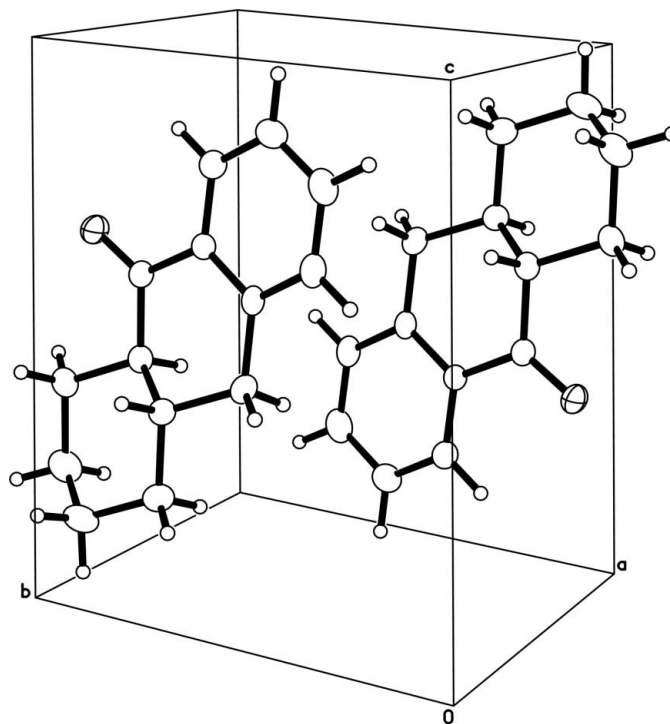


Figure 2
 A packing diagram for (I). Displacement ellipsoids are drawn at the 20% probability level.

Table 1

Hydrogen-bond geometry (Å, °).

<i>D</i> —H... <i>A</i>	<i>D</i> —H	H... <i>A</i>	<i>D</i> ... <i>A</i>	<i>D</i> —H... <i>A</i>
C9A—H9A...O1 ⁱ	0.98	2.66	3.413 (4)	134
C5—H5A...O1 ⁱⁱ	0.98	2.61	3.354 (4)	133

Symmetry codes: (i) $-x + 1, -y + 2, -z + 1$; (ii) $x, y - 1, z$.

All H atoms were found in electron density difference maps but were placed in calculated positions and allowed to refine as riding on their respective C atoms [C—H = 0.98 Å for the aromatic and methine H atoms, C—H = 0.97 Å for the methylene H atoms, and *U*_{iso}(H) = 1.2*U*_{eq}(C)].

Data collection: XSCANS (Siemens, 1996); cell refinement: XSCANS; data reduction: XSCANS; program(s) used to solve structure: SHELXTL (Sheldrick, 1997); program(s) used to refine structure: SHELXTL; molecular graphics: SHELXTL; software used to prepare material for publication: SHELXTL.

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